**Product data sheet** 

# 1. General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 2. Features and benefits

- AEC Q101 compliant
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance

# 3. Applications

Automotive and general purpose power switching

## 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	-	55	V
I <sub>D</sub>	drain current	T <sub>sp</sub> = 25 °C	-	-	7.5	Α
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; <u>Fig. 4</u>	-	-	8.3	W
Static charact	eristics					•
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ °C}$	-	65	80	mΩ
Avalanche rug	gedness					,
E <sub>DS(AL)S</sub>	non-repetitive drain- source avalanche energy	$I_D$ = 2.5 A; $V_{sup} \le$ 25 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped	-	-	30	mJ





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# 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	4	D I
2	D	drain		
3	S	source		G A
4	D	mounting base; connected to drain	⊟1 ⊟2 ⊟3 SC-73 (SOT223)	S sym116

# 6. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
BUK7880-55	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223			
BUK7880-55/CU	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223			

# 7. Marking

Table 4. Marking codes

Type number	Marking code
BUK7880-55	
BUK7880-55/CU	xxYWW 78055

# 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	55	V
$V_{DGR}$	drain-gate voltage	$R_{GS}$ = 20 k $\Omega$	-	55	V
$V_{GS}$	gate-source voltage		-16	16	V
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; <u>Fig. 4</u>	-	8.3	W
I <sub>D</sub>	drain current	T <sub>sp</sub> = 25 °C	-	7.5	Α
		T <sub>sp</sub> = 100 °C	-	4.7	Α

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Parameter	Conditions		Min	Max	Unit
peak drain current	T <sub>sp</sub> = 25 °C; pulsed		-	40	Α
storage temperature			-55	150	°C
junction temperature			-55	150	°C
diode					
source current	T <sub>sp</sub> = 25 °C		-	7.5	Α
peak source current	pulsed; T <sub>sp</sub> = 25 °C		-	40	Α
ggedness					
non-repetitive drain-source avalanche energy	$I_D$ = 2.5 A; $V_{sup}$ ≤ 25 V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	30	mJ
discharge		'			
electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	2	kV
	storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source avalanche energy discharge	storage temperature  junction temperature  diode  source current  peak source current  pulsed; $T_{sp} = 25 ^{\circ}\text{C}$ peak source current  pulsed; $T_{sp} = 25 ^{\circ}\text{C}$ ggedness  non-repetitive drain-source avalanche energy $I_D = 2.5  \text{A};  V_{sup} \le 25 ^{\circ}\text{C};  $	storage temperature  junction temperature  diode  source current  peak source current  pulsed; $T_{sp} = 25 ^{\circ}\text{C}$ peak source current  pulsed; $T_{sp} = 25 ^{\circ}\text{C}$ ggedness  non-repetitive drain-source avalanche energy $I_D = 2.5  \text{A};  V_{sup} \le 25 ^{\circ}\text{C};  \text{unclamped}$ discharge		$ \begin{array}{cccccccccccccccccccccccccccccccccccc$

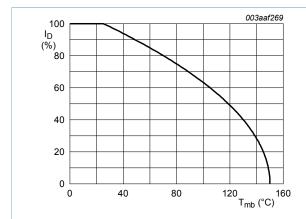
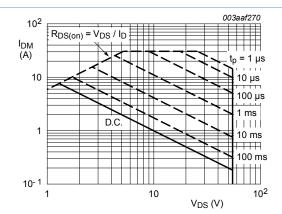


Fig. 1. Normalized continuous drain current as a function of solder point temperature

$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$



 $T_{sp}$  = 25 °C;  $I_{DM}$  is single pulse

Fig. 2. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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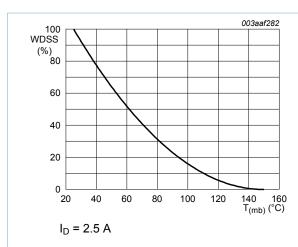


Fig. 3. Normalised drain-source non-repetitive avalanche energy as a function of mountingbase temperature

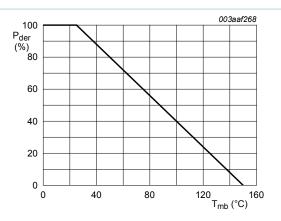


Fig. 4. Normalized total power dissipation as a function of solder point temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

### 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point	mounted on any printed-circuit board	-	12	15	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	Mounted on FR4 PCB, mounting pad for drain 6.5 cm <sup>2</sup>	-	120	-	K/W

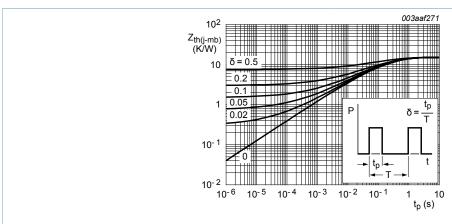


Fig. 5. Transient thermal impedance from junction to solder point as a function of pulse duration

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# 10. Characteristics

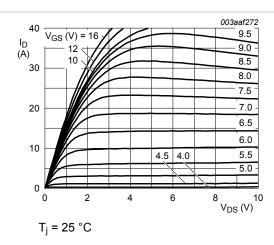
Table 7 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics			'		
(B11)B00	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 ^{\circ}\text{C}$	50	-	-	V
V <sub>GS(th)</sub>	gate-source threshold	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 150 °C	1.2	-	-	V
	voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	4.4	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 55 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.05	10	μA
		V <sub>DS</sub> = 55 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	100	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.04	1	μA
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.04	1	μA
		V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	10	μA
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	10	μA
R <sub>DSon</sub> drain-source	drain-source on-state	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 5 A; T <sub>j</sub> = 150 °C	-	-	148	mΩ
	resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 5 A; T <sub>j</sub> = 25 °C	-	65	80	mΩ
V <sub>(BR)GSS</sub>	gate-source	V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C; I <sub>G</sub> = 1 mA	16	-	-	V
	breakdown voltage	V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C; I <sub>G</sub> = -1 mA	16	-	-	V
Dynamic (	characteristics					
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;	-	365	500	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C	-	110	135	pF
C <sub>rss</sub>	reverse transfer capacitance		-	60	85	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 30 V; $R_L$ = 4.3 $\Omega$ ; $V_{GS}$ = 10 V;	-	9	14	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega; T_{mb} = 25 °C; I_D = 7 A$	-	15	25	ns
t <sub>d(off)</sub>	turn-off delay time		-	18	27	ns
t <sub>f</sub>	fall time		-	12	18	ns
9 <sub>fs</sub>	transfer conductance	V <sub>DS</sub> = 25 V; I <sub>D</sub> = 5 A; T <sub>j</sub> = 25 °C	1	4	-	S
Source-dr	ain diode		I	1	1	
V <sub>SD</sub>	source-drain voltage	$I_S = 5 \text{ A}; V_{GS} = 0 \text{ V}; T_j \ge -55 \text{ °C};$ $T_j \le 175 \text{ °C}$	-	0.85	1.1	V
t <sub>rr</sub>	reverse recovery time	I <sub>S</sub> = 5 A; dI <sub>S</sub> /dt = -100 A/μs;	-	38	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS}$ = -10 V; $V_{DS}$ = 30 V; $T_j \ge$ -55 °C; $T_j \le$ 175 °C	-	0.2	-	μC

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Output characteristics: drain current as a function of drain-source voltage; typical values

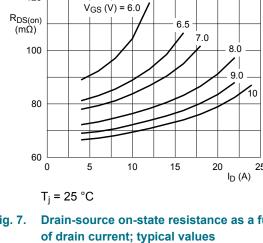
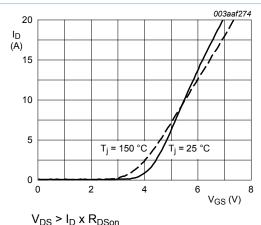


Fig. 7. Drain-source on-state resistance as a function



Transfer characteristics: drain current as a Fig. 8. function of gate-source voltage; typical values

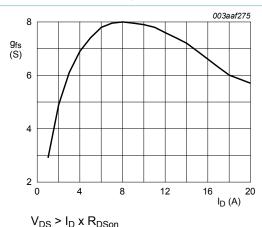


Fig. 9. Forward transconductance as a function of drain current; typical values

maximum

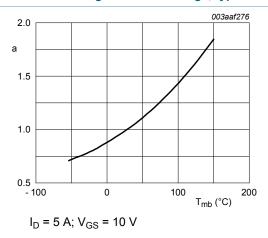
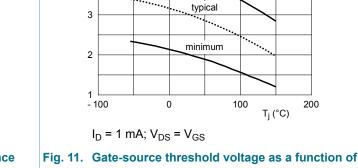


Fig. 10. Normalized drain-source on-state resistance factor as a function of junction temperature



5  $V_{GS(th)}$ 

junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

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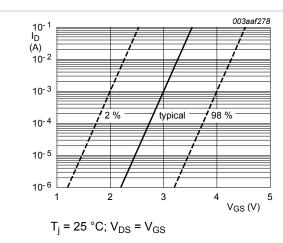


Fig. 12. Sub-threshold drain current as a function of gate-source voltage

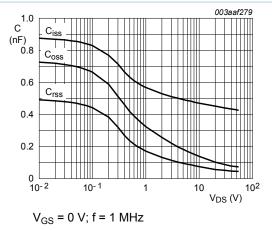


Fig. 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

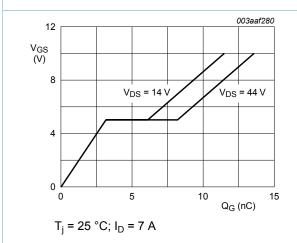


Fig. 14. Gate-source voltage as a function of gate charge; typical values

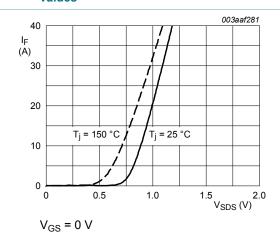
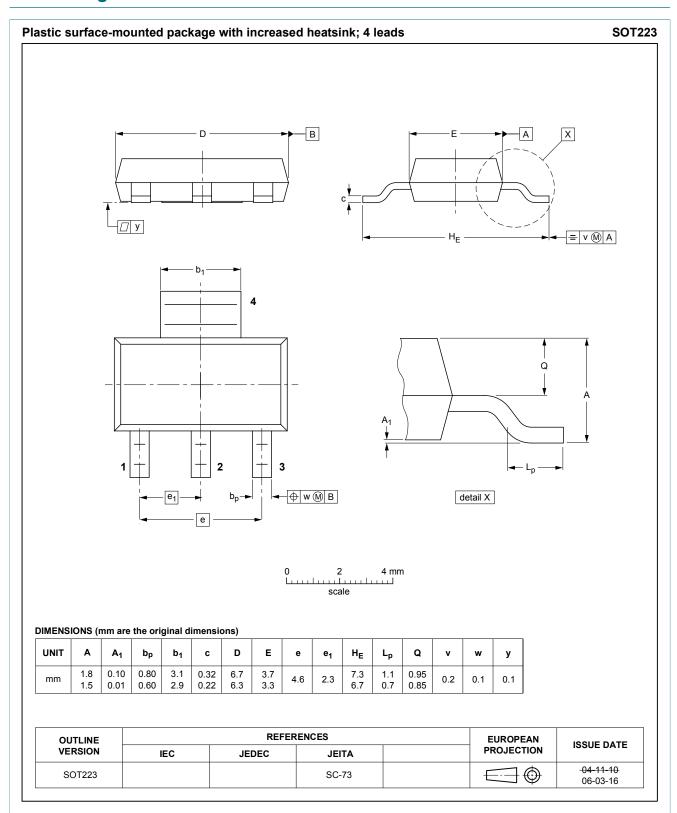


Fig. 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

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# 11. Package outline



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